



- 3 groups work with CR:
- 1) Micro Rel: Microelectronics, terr.CR
 - 2) Rad-Hard: Power electronics, primary CR
 - 3) **GIP CR**: Power electronics, terr. CR

Disclaimer
Focus here on terrestrial
Cosmic Radiation &
Power Devices

Current capabilities and future requirements in radiation testing in Europe

Philipp Bender (GIP GEMS D P T CR)

12/06/2024



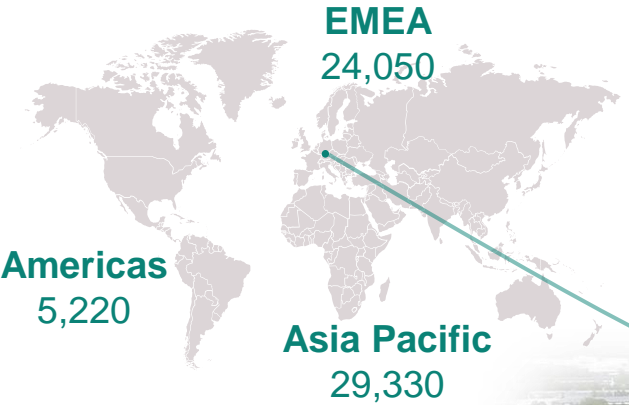
Infineon at a glance: *Driving decarbonization and digitalization*

Employees¹

58,600
employees worldwide

69
R&D and

17
manufacturing locations



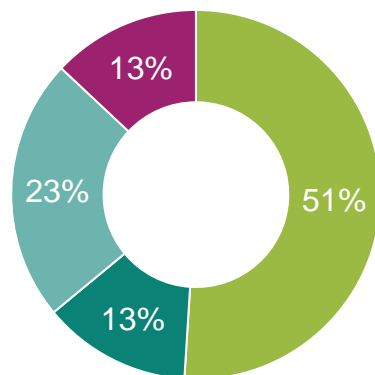
For further information: [Infineon Annual Report](#).
¹ As of 30 September 2023

Infineon at a glance: *Driving decarbonization and digitalization*

– Our growth areas: **Mobility, Energy & IoT**

FY23 revenue by segment¹

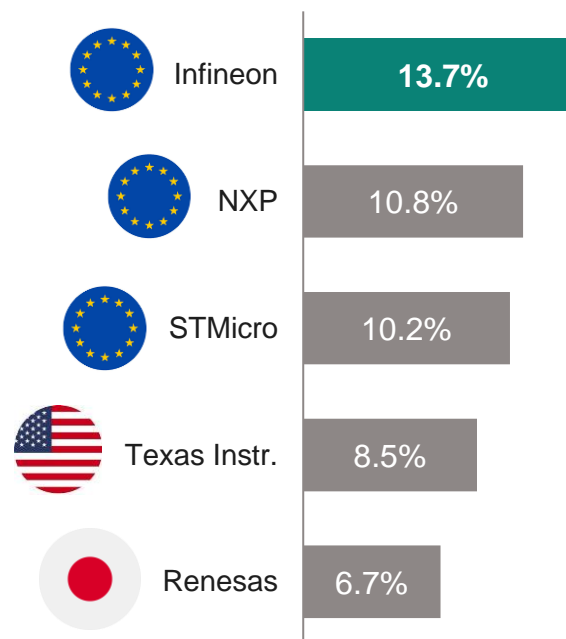
- Automotive (ATV)
- Green Industrial Power (GIP)
- Power & Sensor Systems (PSS)
- Connected Secure Systems (CSS)



Total revenue FY23: 16 bn €

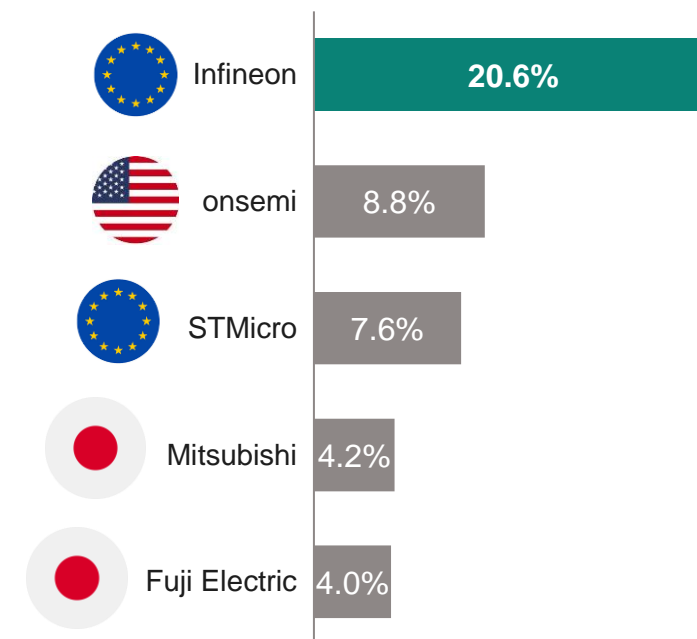
Automotive devices

2023 total global market: USD 69.2bn²



Power modules & disretes

2022 total global market: USD 30.9bn³



¹ 2023 Fiscal year (as of 30 September 2023) | ² TechInsights: Automotive Semiconductor Vendor 2023 Market Shares. April 2024. | ³ Based on or includes research from Omdia: Power Semiconductor Market Share Database – 2022. September 2023. Results are not an endorsement of Infineon Technologies AG. Any reliance on these results is at the third party's own risk.

Reliability issues of Power Semiconductors – Cosmic Radiation (CR)

- Space applications: Heavy ions & high-energy protons of primary CR can provoke power device failure
- **Ground-level applications:** Terrestrial CR (TCR) can cause Single-Event Breakdown (SEB) of **power devices**

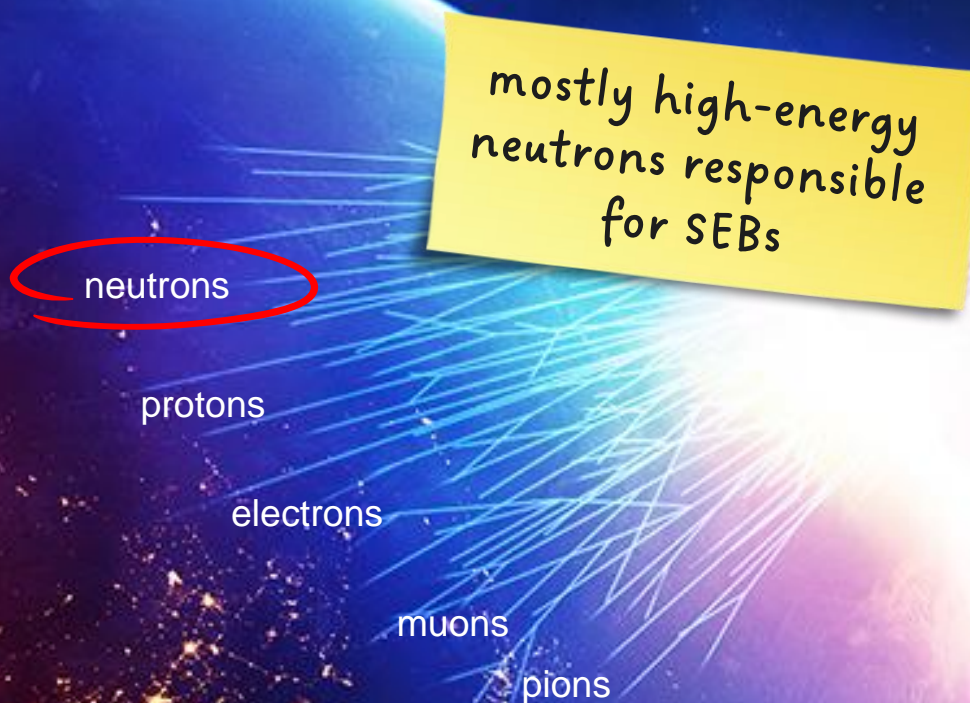


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“Current capabilities and future requirements in radiation testing in Europe”

A yellow rectangular sticky note with a slight shadow, tilted slightly to the right. It contains the text "Disclaimer Focus here on TCR & Power Devices" in a black, handwritten-style font.

Disclaimer
Focus here on TCR &
Power Devices

1 How do we test terrestrial CR reliability of power devices?

2 What are our future requirements?

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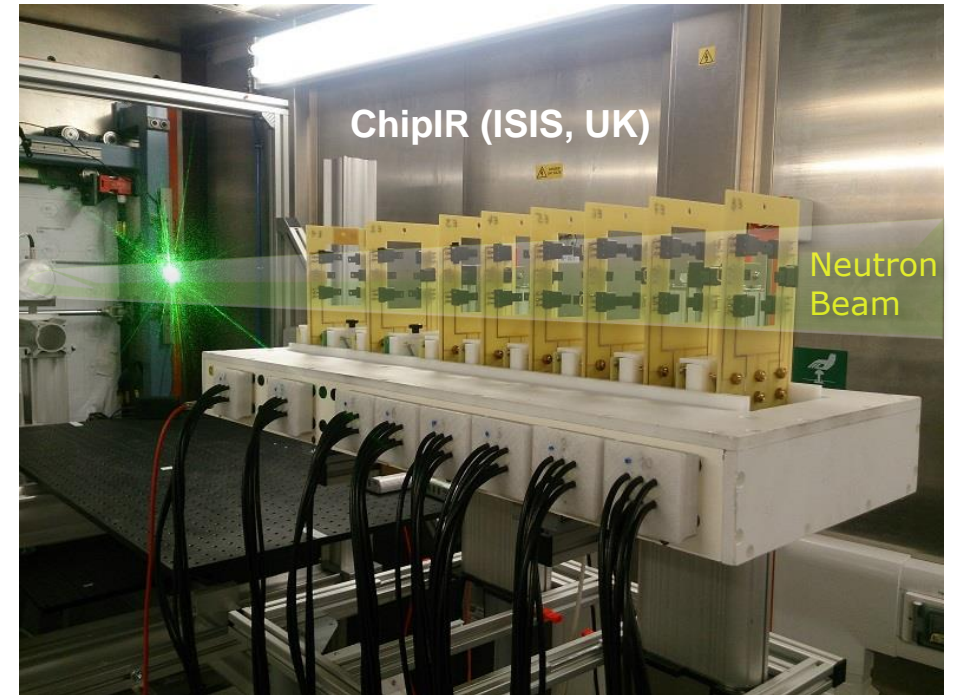
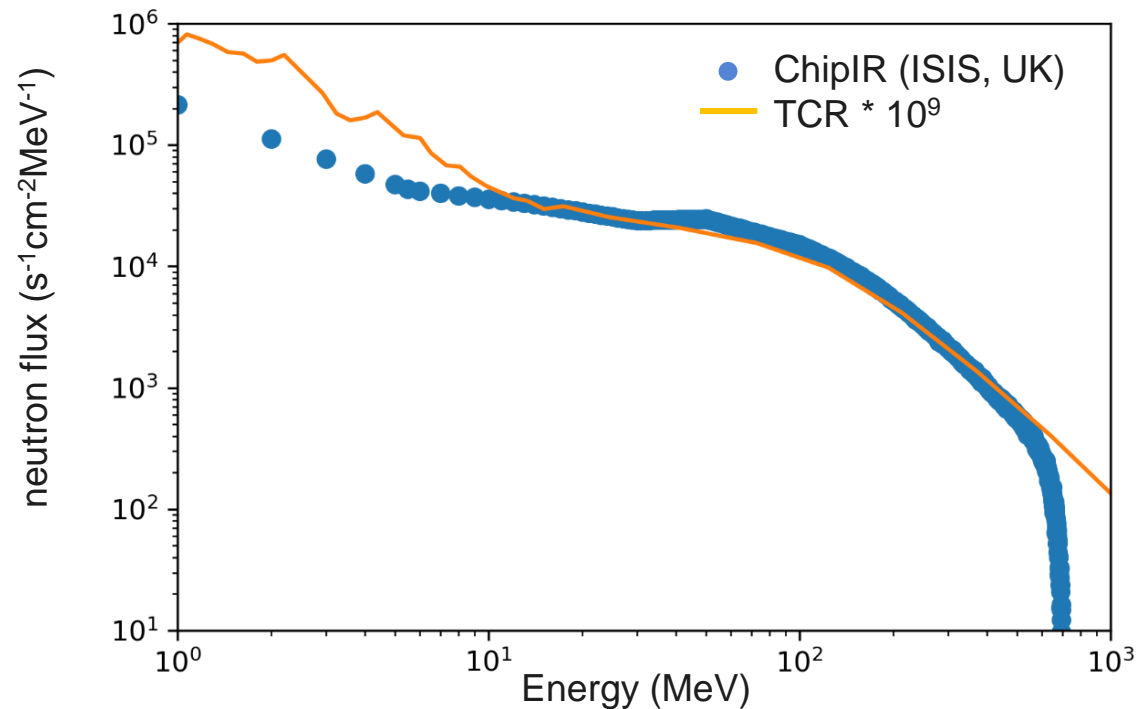
- 1 How do we test terrestrial CR reliability of power devices?
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1. How do we test TCR reliability of power devices?

- We perform CR robustness tests using natural TCR (in lab or high altitudes)
- BUT: Standard tests are done using artificial high-flux nucleon beams (neutrons or protons)
- Following the JEDEC standard JEP151 “*Test Procedure for the Measurement of Terrestrial Cosmic Ray Induced Destructive Effects in Power Semiconductor Devices*”:
 - beam: either monoenergetic protons or neutrons, or neutron beams with spallation energy spectrum (> 150 MeV)
 - devices: 30 – 50 devices must be simultaneously in beam path and tested in off-state with applied static voltage
 - failures: device fails must be unequivocally identified and recorded during irradiation
 - result: 3 – 5 data points *FIT* vs *V* (*FIT*: Failures in Time, 1 *FIT* = 1 fail in 10^9 hours)

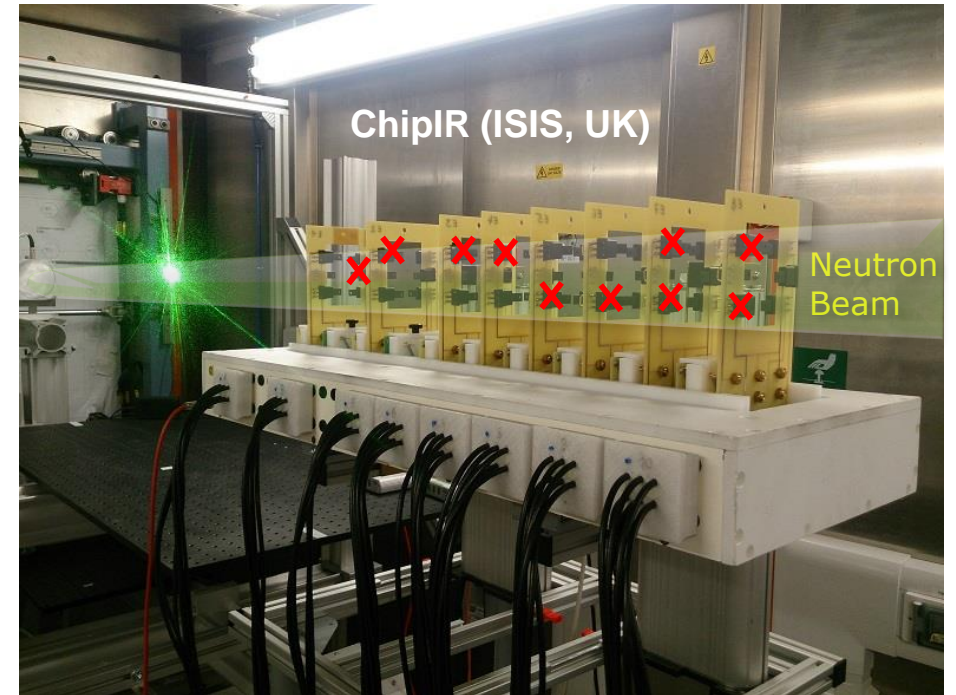
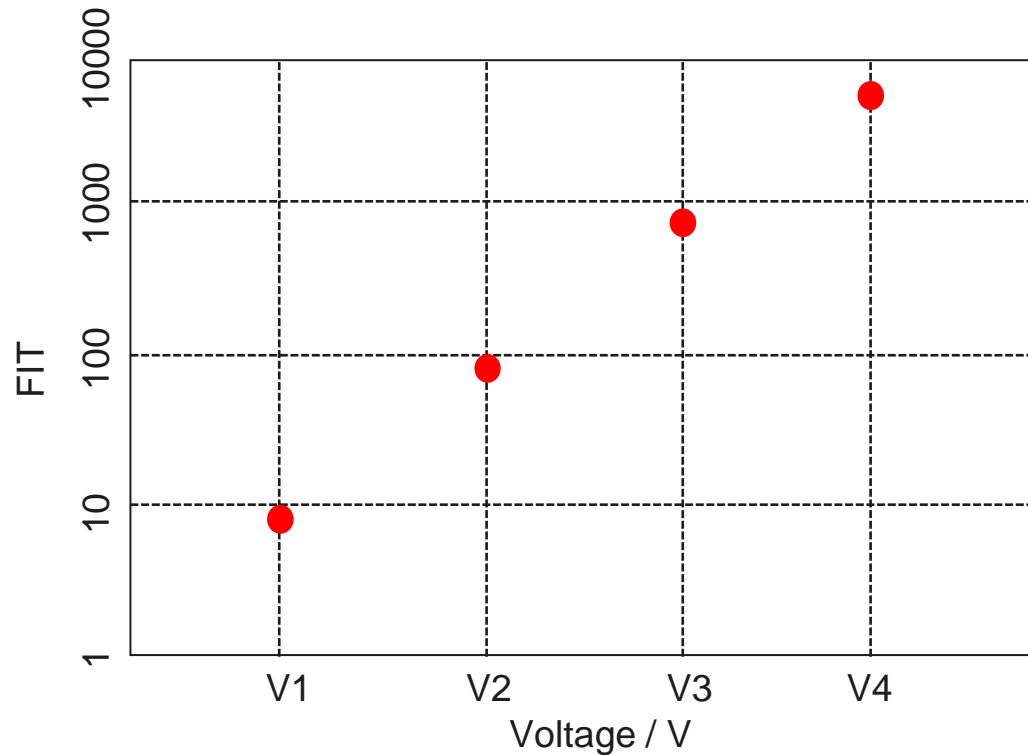
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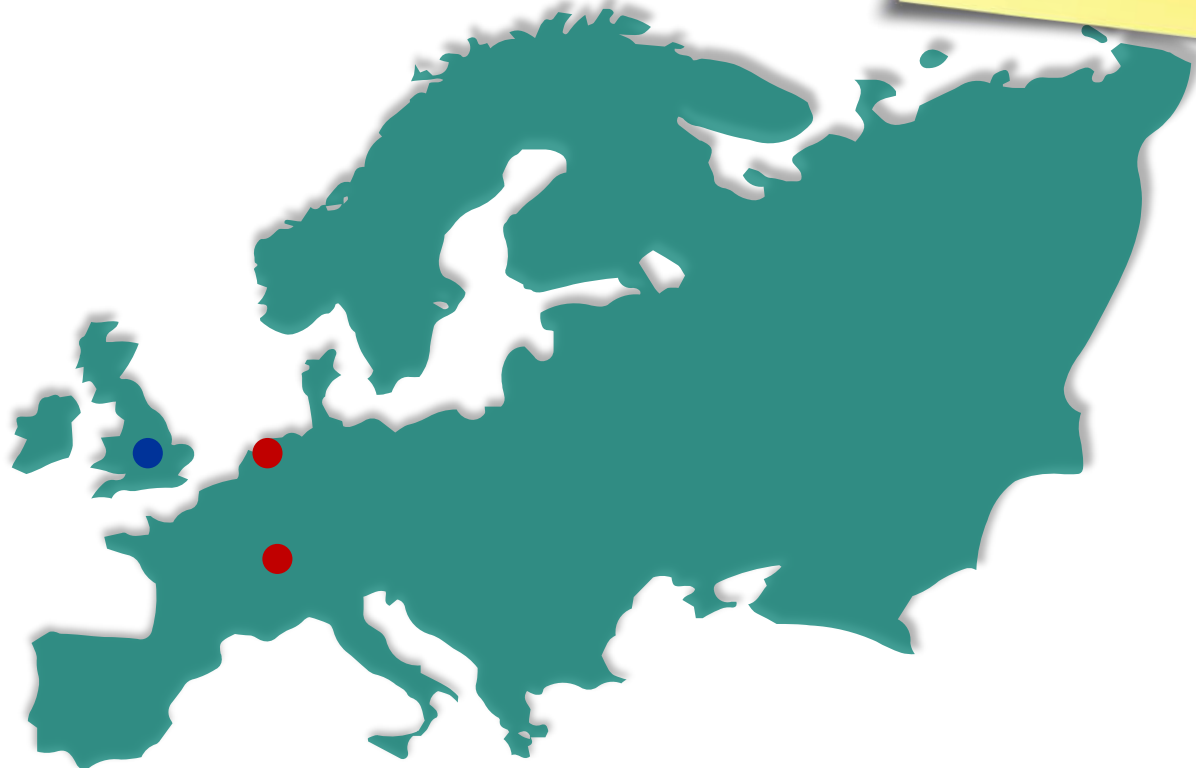
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1. How do we test TCR reliability of power devices?

*“Current capabilities
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Neutrons (spectrum)

● STFC-ISIS

Protons (monoenergetic)

● PARTREC

● PSI

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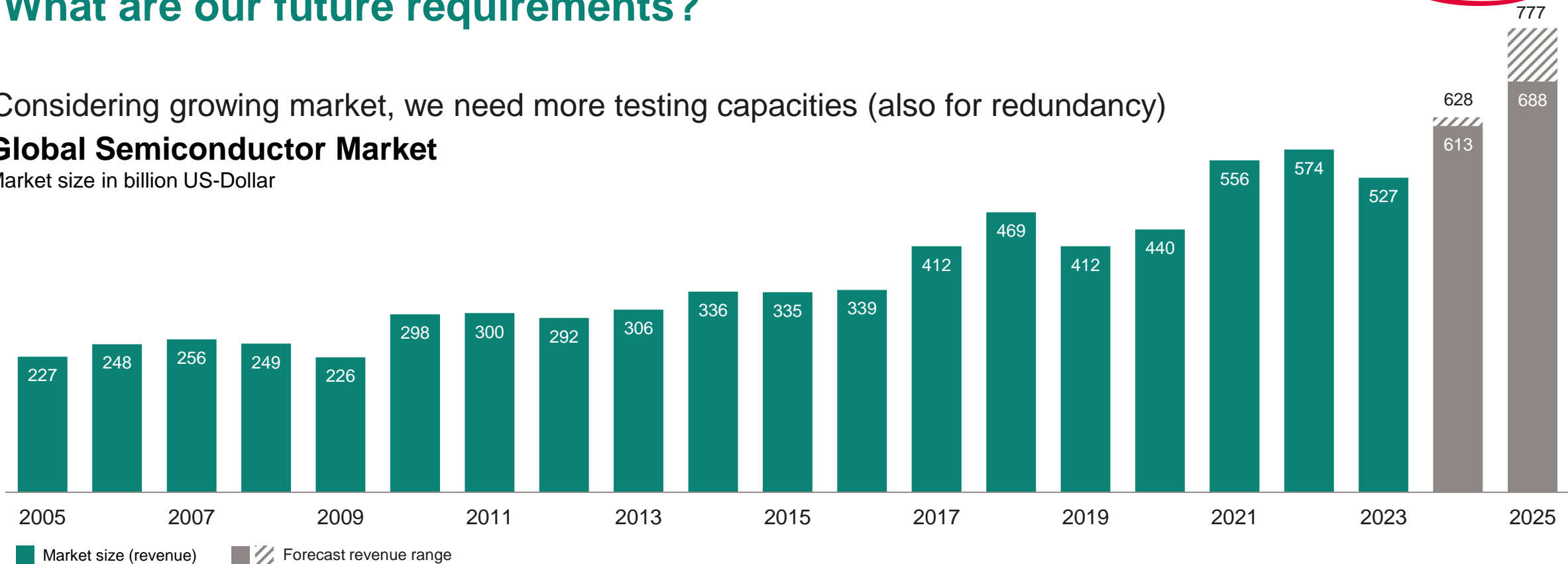
2 What are our future requirements?

2. What are our future requirements?

- Considering growing market, we need more testing capacities (also for redundancy)

Global Semiconductor Market

Market size in billion US-Dollar



Source: WSTS for historical data. | Forecast: of WSTS, Omdia, Gartner, TechInsights; last update 2 May 2024.

- We need second instrument with neutron spallation energy spectrum in Europe
- Currently, only spallation source where ChipIR-like instrument could be built is ESS

2. What are our future requirements?

We go every 2 – 3 months to a testing campaign, 1 campaign are 2 – 3 days of beamtime
 One test takes 20 – 60 min → usually 20 – 60 tests per campaign



- Requirements for standard tests:
 - Either monoenergetic beams or neutron beams with spallation energy spectrum (> 150 MeV, ideally up to 1 GeV)
 - Flux densities $1e6$ n/cm²/sec – $1e8$ n/cm²/sec (ideally tunable)
 - Beam with *constant* flux, high spatial uniformity and low divergence
 - Diameter > 10 cm but < 20 cm to reduce irradiation of electronics
 - Precise value for flux must be provided to obtain correct *FIT* values
 - Enough room to position setup and surrounding electronics
 - Easy access to setup to change devices fast (time = money)

- Fast access to get beamtime (regular visits necessary)
- Low travel costs & organizational effort → Europe

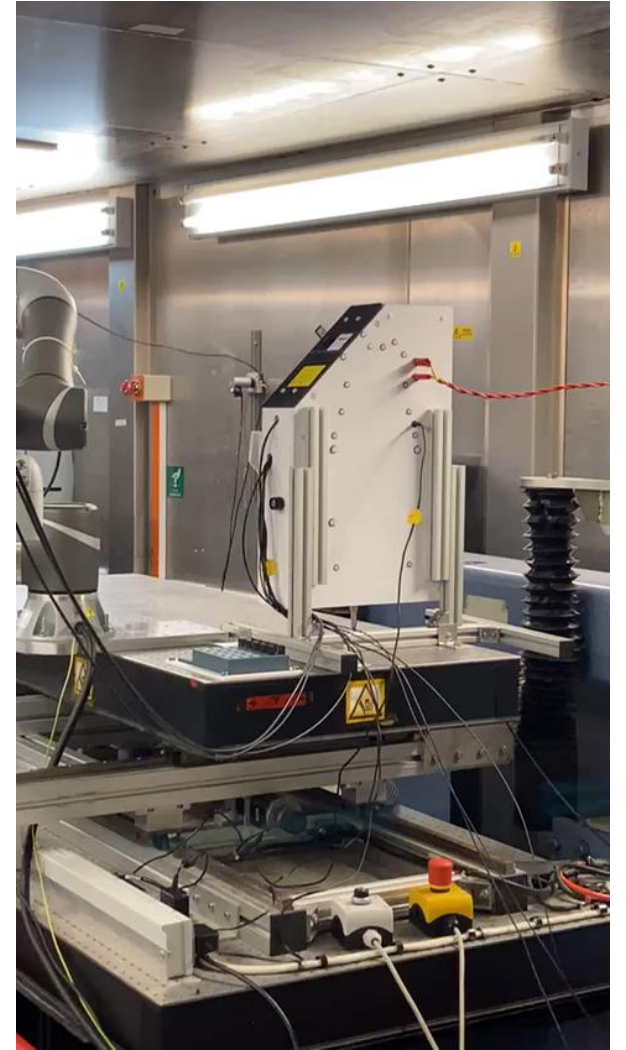


2. What are our future requirements?

- Requirements for instruments regarding standard tests:
 - Either monoenergetic beams or neutron beams with spallation energy spectrum
 - Flux densities $1e6$ n/cm²/sec – $1e8$ n/cm²/sec (ideally tunable)
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- In case of new instrument, we would like to be involved during design stage

- Additional options:
 - Thermo-streamer for low-temperature measurements
 - Collaboration regarding automation of measurements
 - longterm ideally completely remote experiments

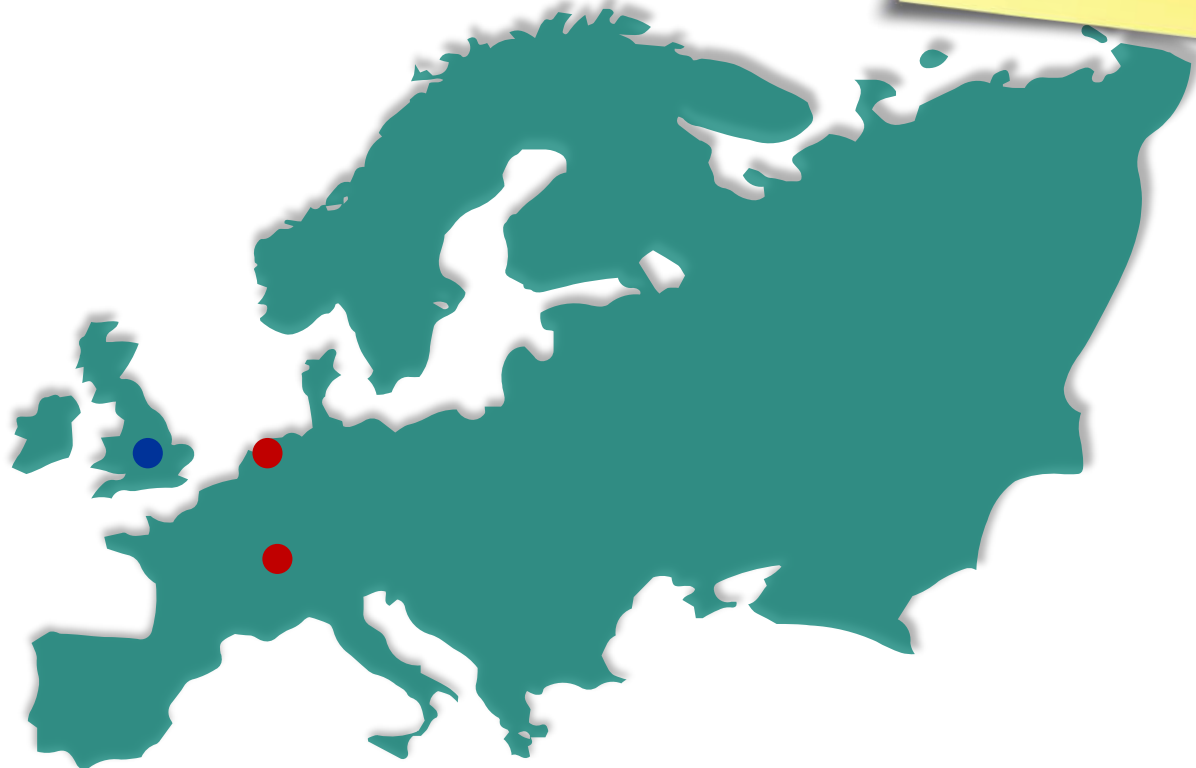


https://www.isis.stfc.ac.uk/Pages/SH24_InfineonRobot.aspx

2. What are our future requirements?

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Neutrons (spectrum)

- STFC-ISIS

Protons (monoenergetic)

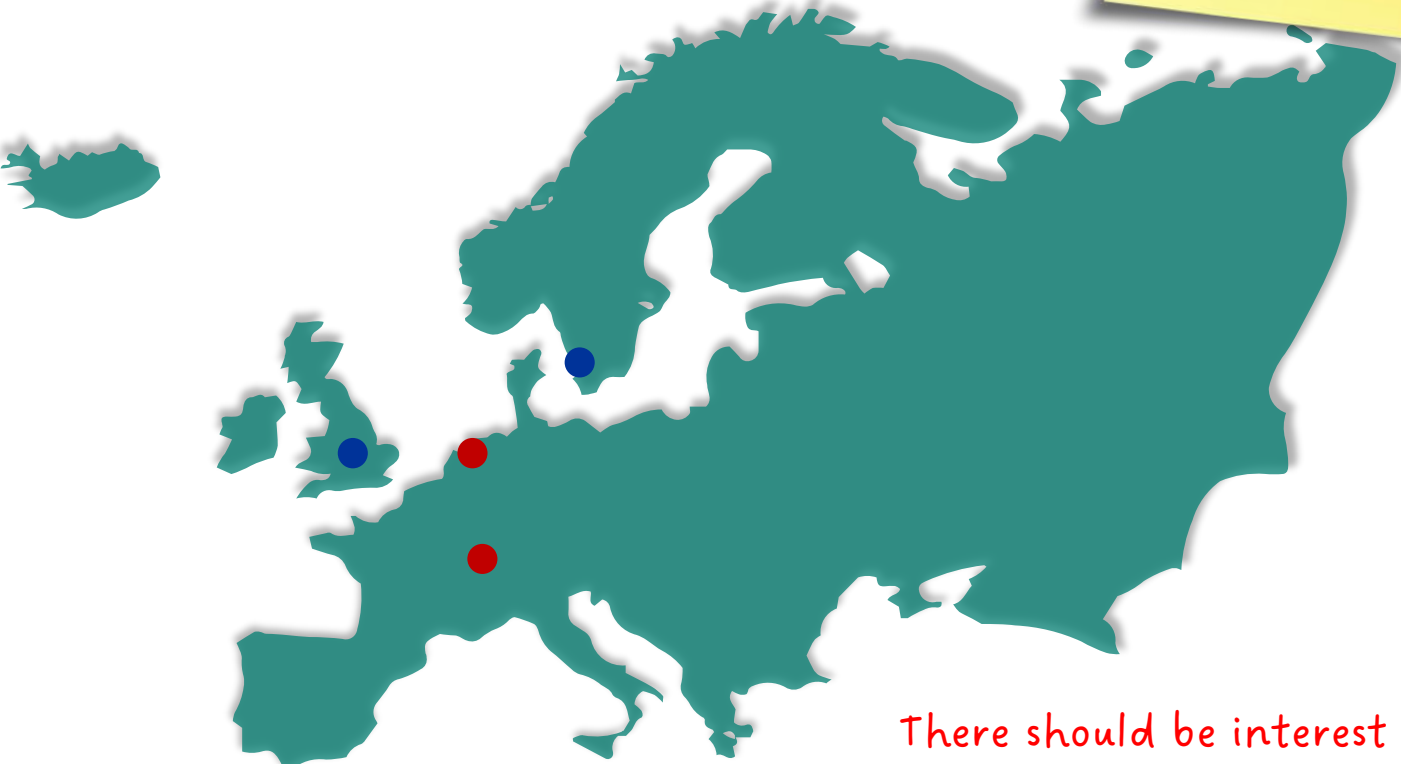
- PARTREC
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2. What are our future requirements?

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Micro Rel colleagues would also use new instrument provided certain requirements are met



Neutrons (spectrum)

● STFC-ISIS

● ESS

Protons (monoenergetic)

● PARTREC

● PSI

There should be interest from several European companies to build instrument
→ business case

